

# Essentials of MOSFETs

## Unit 4: Transmission Theory of the MOSFET

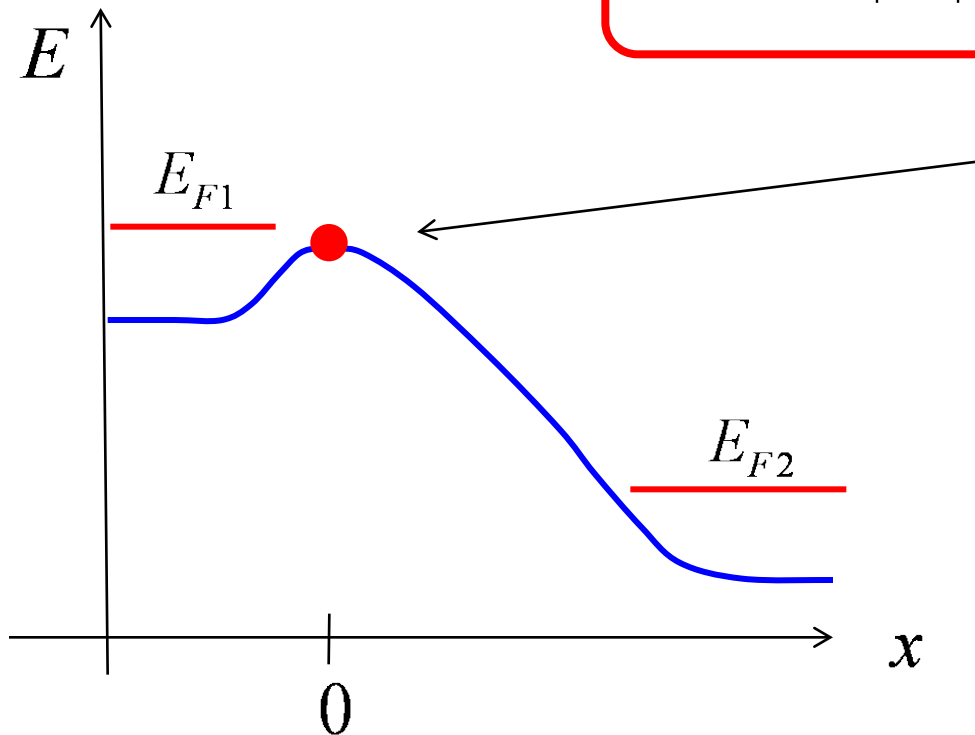
### Lecture 4.4: Velocity at the Virtual Source

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# Focus on the top of the barrier (the VS)

$$I_D = W|Q_n|\langle v_x \rangle$$



- 1) We know the charge at the VS.
- 2) What is the velocity at the VS?
- 3) How does it depend on  $V_{DS}$  and  $V_{GS}$ ?

# Approach

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Definition of current:

$$I_D = W \left| Q_n(x=0, V_{GS}, V_{DS}) \right| \left\langle v_x(x=0, V_{GS}, V_{DS}) \right\rangle$$

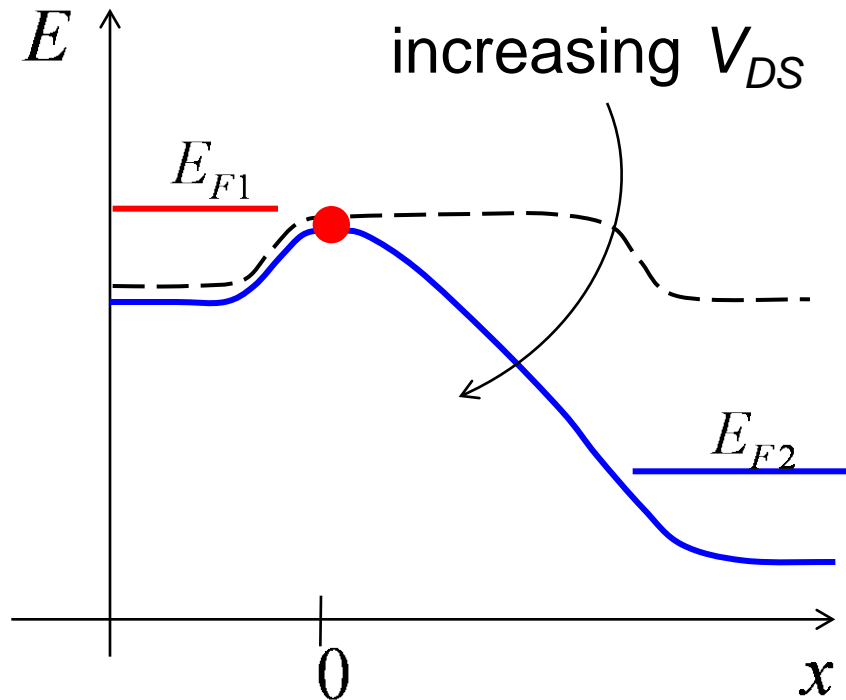
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Ballistic IV:

$$I_D = W \left| Q_n(x=0, V_{GS}, V_{DS}) \right| v_T \left( \frac{1 - e^{-qV_{DS}/k_B T}}{1 + e^{-qV_{DS}/k_B T}} \right)$$

(assumes nondegenerate conditions)

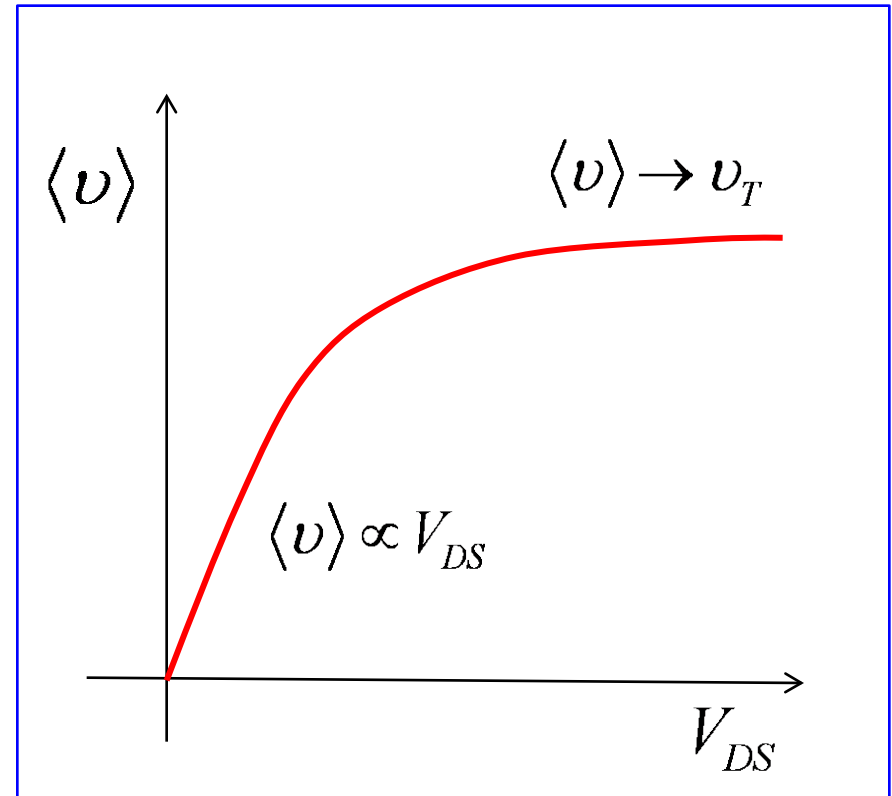
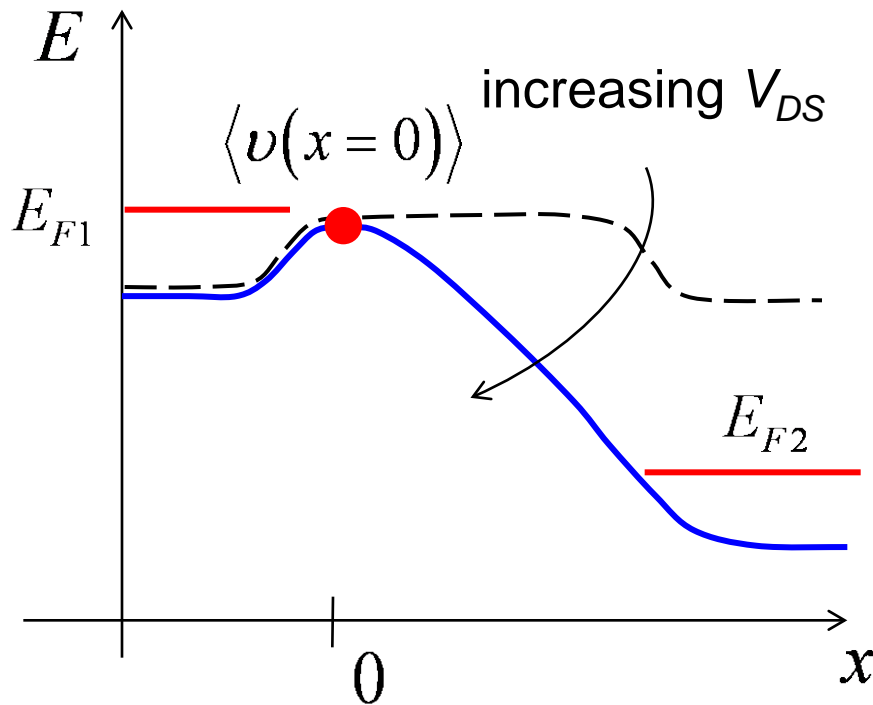
# Average velocity at the VS



$$\langle v_x(x=0) \rangle = v_T \frac{(1 - e^{-qV_{DS}/k_B T})}{(1 + e^{-qV_{DS}/k_B T})}$$

(nondegenerate carrier statistics)

# Velocity vs. $V_{DS}$



$$\langle v_x(x=0) \rangle = v_T \frac{(1 - e^{-qV_{DS}/k_B T})}{(1 + e^{-qV_{DS}/k_B T})}$$

# Velocity for small $V_{DS}$

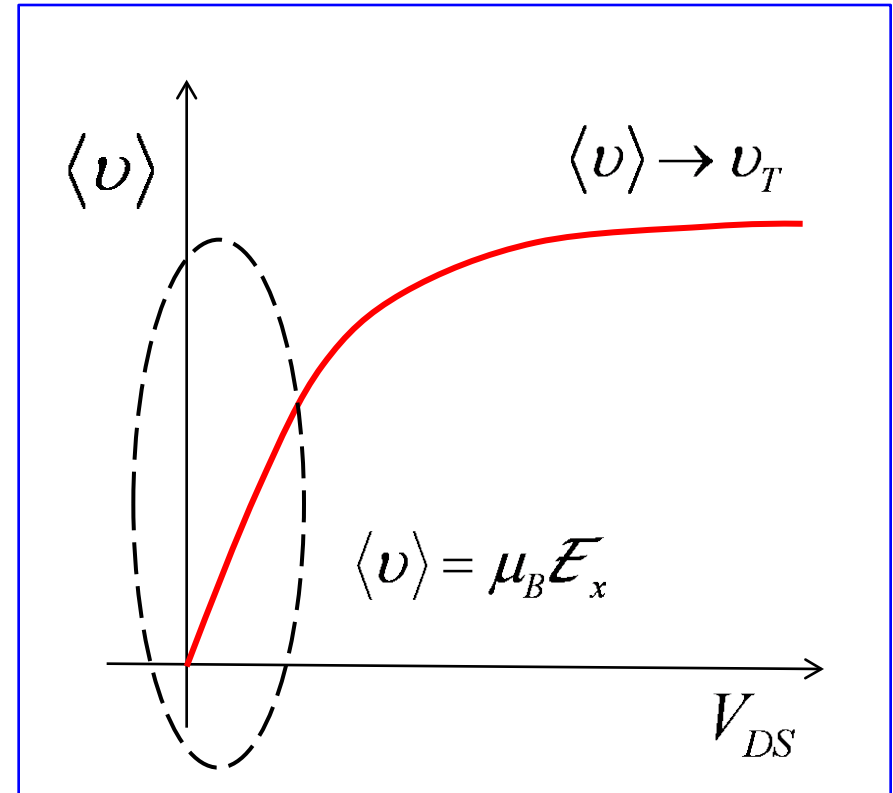
$$\langle v(x=0) \rangle = v_T \frac{(1 - e^{-qV_{DS}/k_B T})}{(1 + e^{-qV_{DS}/k_B T})}$$

$$V_{DS} \ll k_B T / q \quad e^x \approx 1 + x$$

$$\langle v(x=0) \rangle = \frac{v_T}{2(k_B T / q)} V_{DS}$$

$$\langle v(x=0) \rangle = \left( \frac{v_T L}{2(k_B T / q)} \right) \left( \frac{V_{DS}}{L} \right)$$

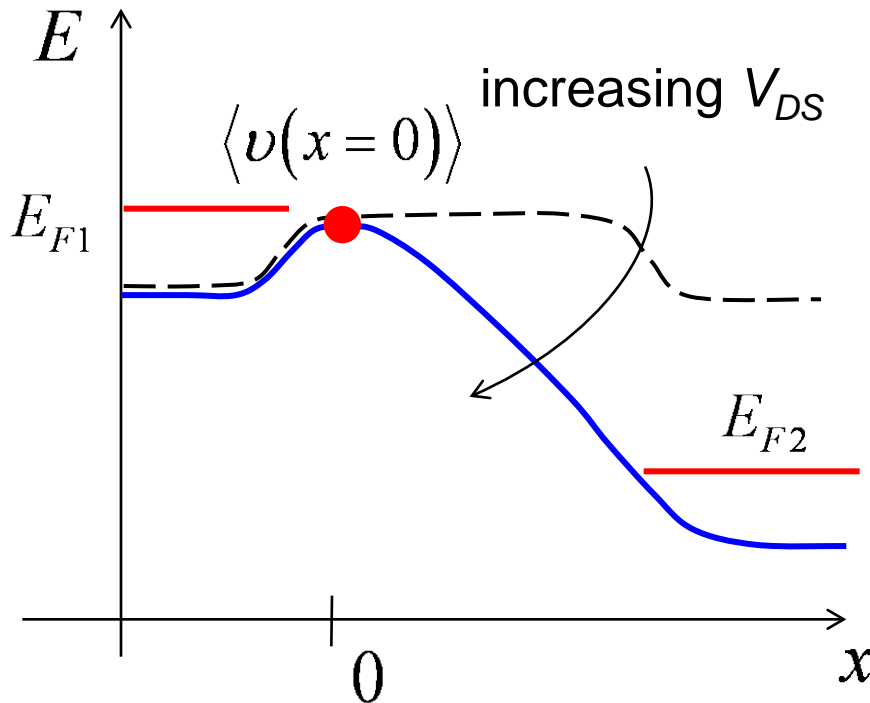
$$\mu_B \equiv \frac{v_T L}{2(k_B T / q)} \quad \text{cm}^2/\text{V-s}$$



$$\langle v(x=0) \rangle = \mu_B \mathcal{E}_x$$

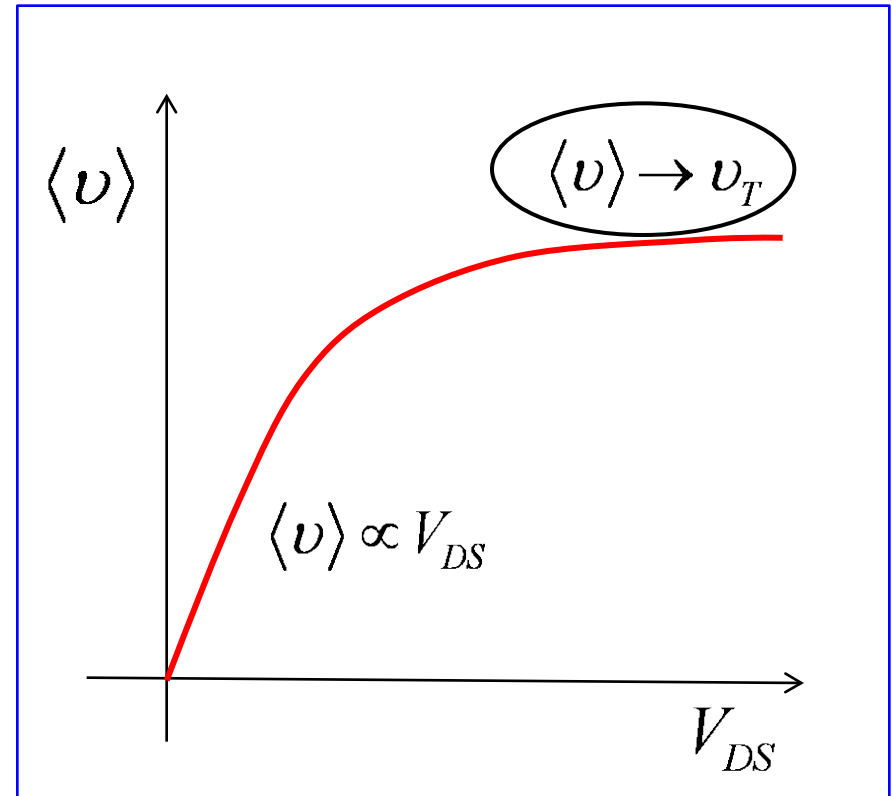
“ballistic mobility”

# Velocity for large $V_{DS}$



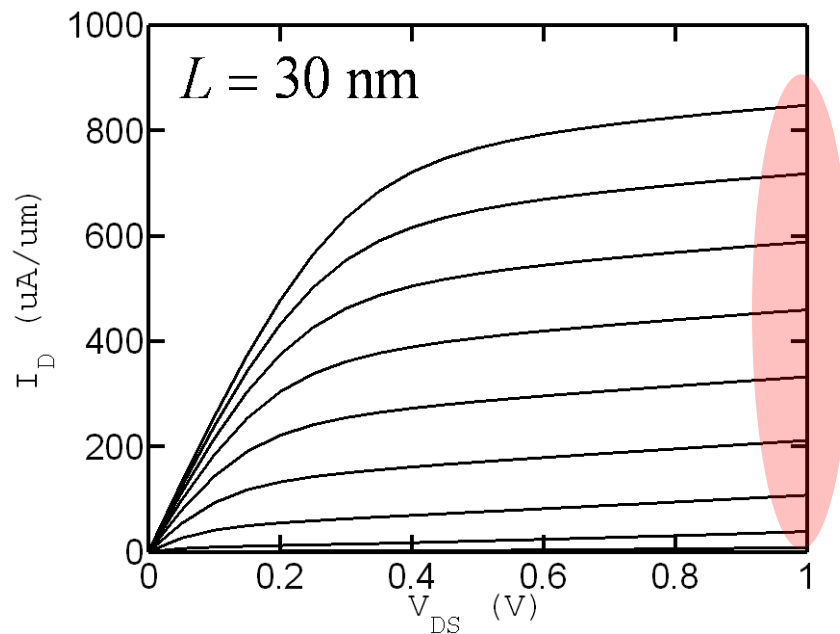
$$\langle v_x(x=0) \rangle = v_T \frac{(1 - e^{-qV_{DS}/k_B T})}{(1 + e^{-qV_{DS}/k_B T})}$$

$$V_{DS} \gg k_B T / q$$



The velocity at the VS **saturates** in a ballistic MOSFET.

# The “signature” of velocity saturation in MOSFETs



$$I_D \propto (V_{GS} - V_T)^1$$

ETSOI MOSFET data provided by A. Majumdar, IBM Research, 2015.



# Physics of velocity saturation

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In a long channel MOSFET with a high electric field, the carrier velocity saturates at high drain bias because of **strong scattering**.

It saturates in the high-field region **near the drain**.

In a ballistic MOSFET there is no scattering, but the velocity saturates at high drain bias.

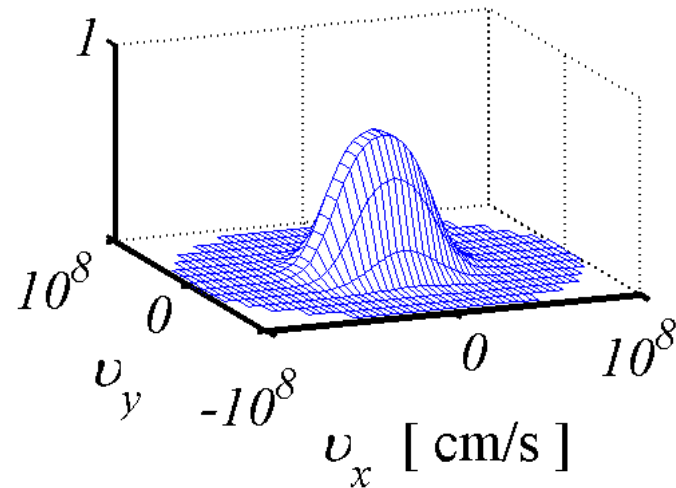
It saturates at the  $V_S$ , where the E-field is zero.

What is the physics of velocity saturation in a ballistic MOSFET?

# Equilibrium Maxwellian velocity distribution

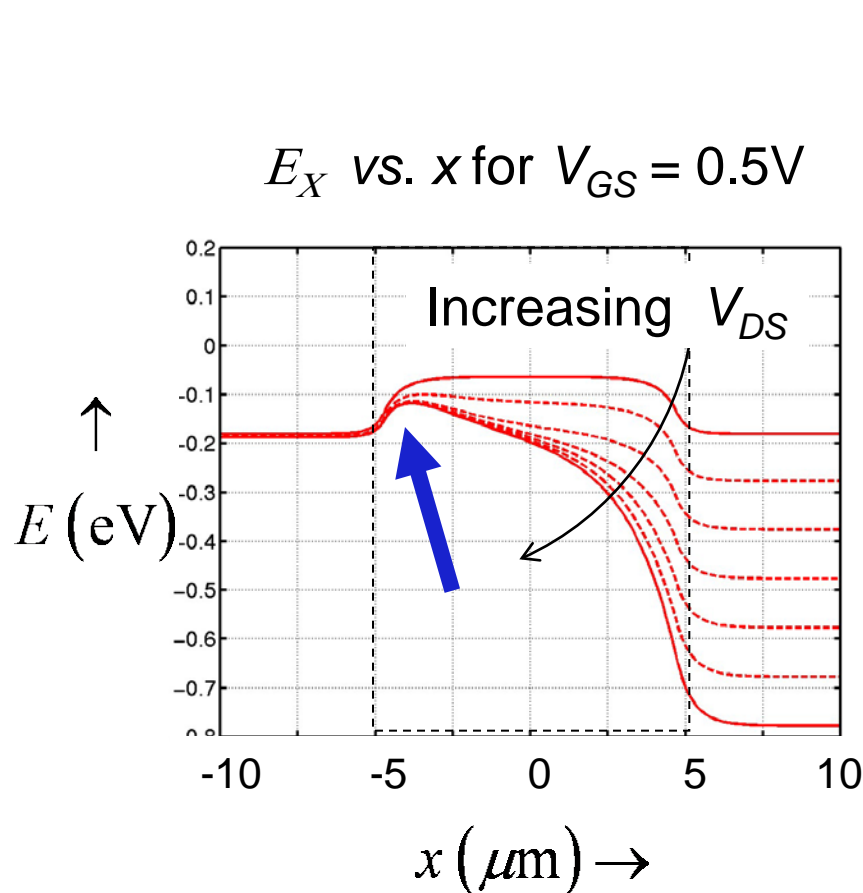
$$f_0(E) = \frac{1}{1 + e^{(E-E_F)/k_B T}} \quad f_0(E) \approx e^{-(E-E_F)/k_B T} \quad E = E_C + \frac{m^* v^2}{2} \quad v^2 = v_x^2 + v_y^2$$

$$f_0(v_x, v_y) \propto e^{-m^*(v_x^2 + v_y^2)/2k_B T}$$

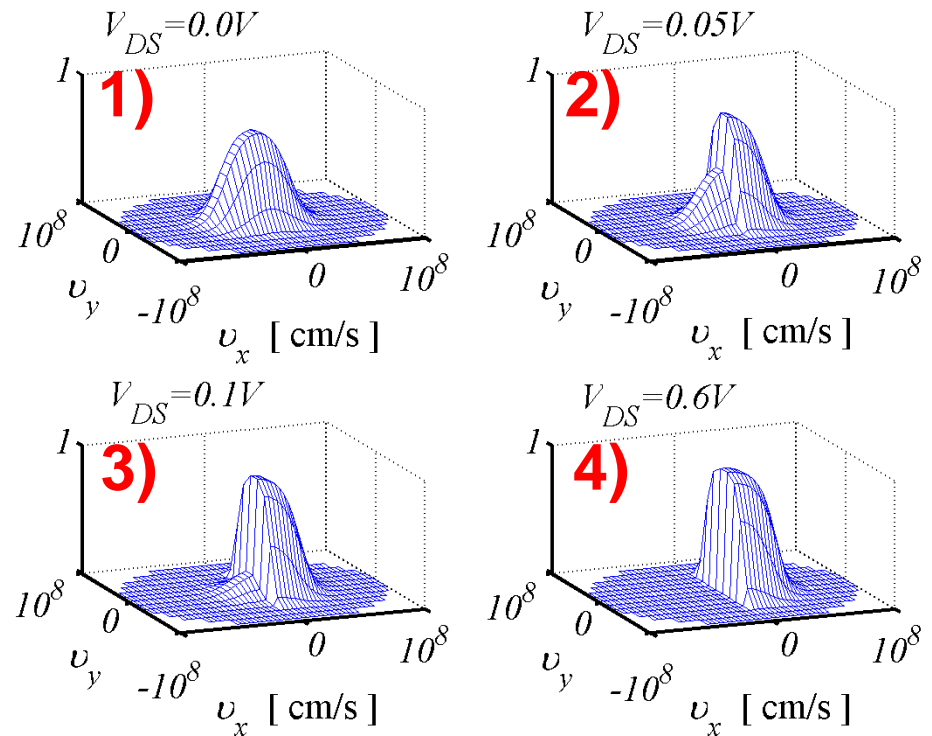


In the bulk, scattering maintains equilibrium.

# Filling states at the top of the barrier

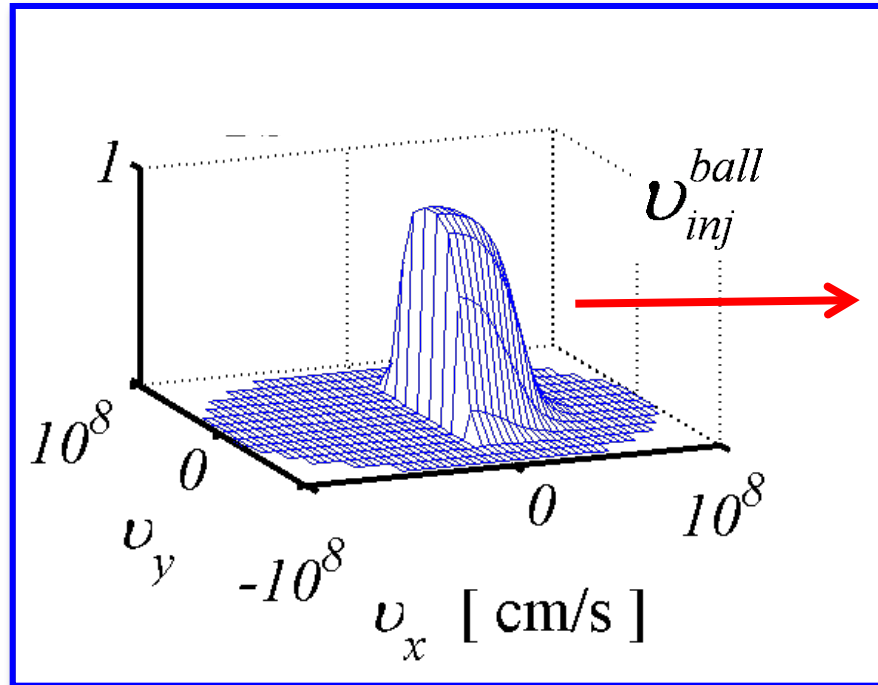


$$f(v_x, v_y)$$



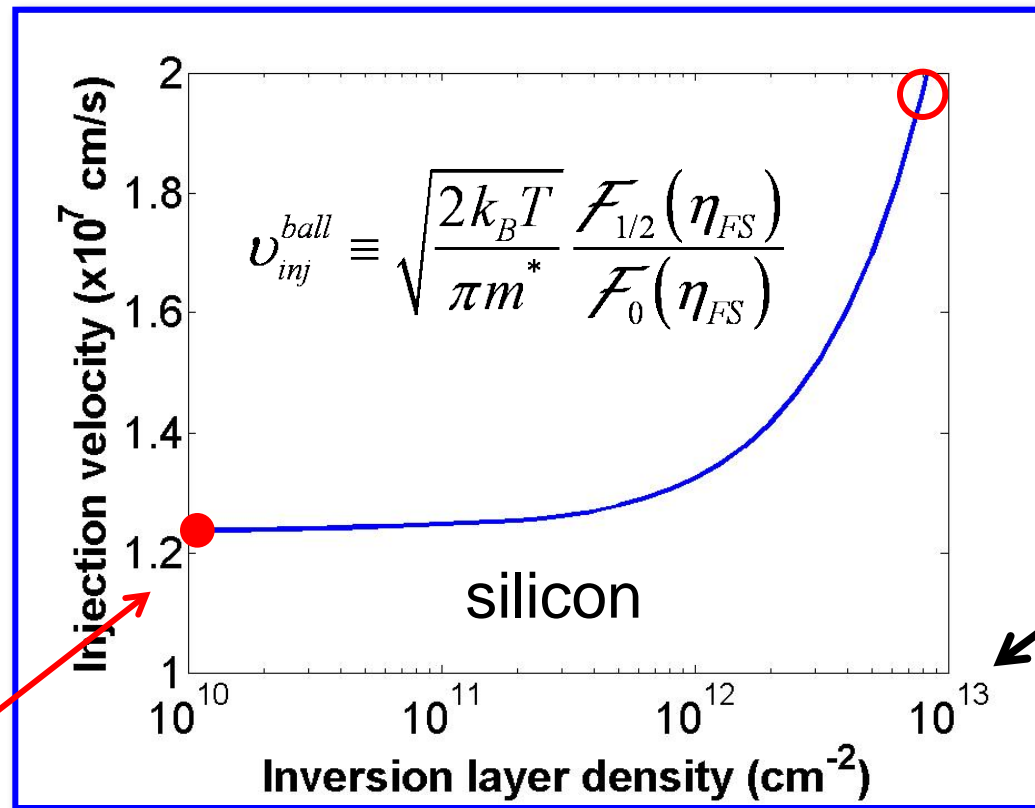
(Numerical simulations of an  $L = 10$  nm double gate Si MOSFET from J.-H. Rhew and M.S. Lundstrom, *Solid-State Electron.*, **46**, 1899, 2002)

# Ballistic injection velocity



$$\langle\langle v_x(0) \rangle\rangle = v_{inj}^{ball}(E_{F1}) = v_T \frac{\mathcal{F}_{1/2}(\eta_{F1})}{\mathcal{F}_0(\eta_{F1})} \quad v_{inj}^{ball} = v_T = \sqrt{\frac{2k_B T}{\pi m^*}} \quad (\text{nondegenerate})$$

# Gate voltage dependent ballistic injection velocity



$$v_T = \sqrt{\frac{2k_B T}{\pi m^*}}$$

non-degenerate

$$m^* = 0.19m_0$$

## For more discussion

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To see how Fermi-Dirac statistics are included in the analysis, see:

Lecture 14 in:

Mark Lundstrom, *Fundamentals of Nanotransistors*,  
World Scientific Publishing Co., Singapore, 2018.

# Summary

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In a ballistic MOSFET, the velocity saturates for high drain voltages.

But it saturates at the top of the barrier (the  $V_S$ ) where the electric field is zero.

The velocity saturates at the **ballistic injection velocity**, which is a key figure of merit for a transistor.

# Next topic

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We knew how to treat the diffusive case, where there is a lot of carrier scattering (with the traditional model).

We now know how to treat the ballistic case, where there is no scattering (with the ballistic model).

How do we treat MOSFETs between these two limits?

That is the subject of the next lecture.